

### AO6804



# **Common-Drain Dual N-Channel Enhancement Mode Field Effect Transistor**

# **General Description**

The AO6804 uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a load switch or in PWM applications. AO6804 is Pb-free (meets ROHS & Sony 259 specifications).

### **Features**

 $V_{DS} = 20V$ 

 $I_D = 5.0A$   $(V_{GS} = 4.5V)$ 

### Typical Rds

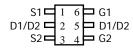
 $R_{DS(ON)} < 24m\Omega (V_{GS} = 4.5V)$ 

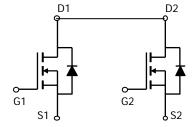
 $R_{DS(ON)}$  < 26m $\Omega$  ( $V_{GS}$  = 4.0V)

 $R_{DS(ON)} < 28m\Omega (V_{GS} = 3.1V)$ 

 $R_{DS(ON)}$  < 31m $\Omega$  ( $V_{GS}$  = 2.5V)

# TSOP6 Top View





## Absolute Maximum Ratings T<sub>A</sub>=25°C unless otherwise noted

Parameter		Symbol	10 Sec	Steady State	Units
Drain-Source Voltage		$V_{DS}$	20		V
Gate-Source Voltage		$V_{GS}$	±12		V
Continuous Drain	T <sub>A</sub> =25°C		5	4	
Current <sup>A</sup>	T <sub>A</sub> =70°C	I <sub>D</sub>	4	3.2	Α
Pulsed Drain Current B		$I_{DM}$	25		
Power Dissipation <sup>A</sup>	T <sub>A</sub> =25°C	В	1.3	8.0	W
	T <sub>A</sub> =70°C	$-P_{D}$	0.8	0.5	VV
Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>STG</sub>	-55 to 150		°C

Thermal Characteristics							
Parameter		Symbol	Тур	Max	Units		
Maximum Junction-to-Ambient A	t ≤ 10s	$R_{\scriptscriptstyle{ hetaJA}}$	76	95	°C/W		
Maximum Junction-to-Ambient A	Steady State	IN <sub>θ</sub> JA	118	150	°C/W		
Maximum Junction-to-Lead <sup>C</sup>	Steady State	$R_{ hetaJL}$	54	68	°C/W		

#### Electrical Characteristics (T<sub>J</sub>=25°C unless otherwise noted)

Symbol	Parameter	Conditions		Тур	Max	Units
STATIC F	PARAMETERS					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	20			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 20V, V <sub>GS</sub> = 0V			1	μА
		$T_J = 55^{\circ}C$			5	
I <sub>GSS</sub>	Gate-Body leakage current	$V_{DS} = 0V, V_{GS} = \pm 12V$			±500	nA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS} I_{D} = 250 \mu A$	0.5	0.75	1.2	V
I <sub>D(ON)</sub>	On state drain current	$V_{GS} = 4.5V, V_{DS} = 5V$	25			Α
R <sub>DS(ON)</sub>		$V_{GS} = 4.5V, I_D = 5.0A$	18	24	32	C
		T <sub>J</sub> =125°C	25	33	43	mΩ
	Static Drain-Source On-Resistance	V <sub>GS</sub> = 4.0V, I <sub>D</sub> = 4.5A	22	26	34	mΩ
		V <sub>GS</sub> = 3.1V, I <sub>D</sub> = 4.5A	21	28	37	mΩ
		V <sub>GS</sub> = 2.5V, I <sub>D</sub> = 4.0A	22	31	42	mΩ
g <sub>FS</sub>	Forward Transconductance	$V_{DS} = 5V, I_{D} = 5.0A$		7		S
$V_{SD}$	Diode Forward Voltage	$I_S = 1A, V_{GS} = 0V$		0.65	1	V
I <sub>S</sub>	Maximum Body-Diode Continuous Current				1.1	Α
DYNAMIC	CPARAMETERS					
C <sub>iss</sub>	Input Capacitance			580	725	pF
C <sub>oss</sub>	Output Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =10V, f=1MHz		95		pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1		70		pF
R₀	Gate resistance	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V, f=1MHz		3.5	5.3	Ω
SWITCHI	NG PARAMETERS			•	•	
$Q_g$	Total Gate Charge			5.8	7.7	nC
$Q_{gs}$	Gate Source Charge	$V_{GS}$ = 4.5V, $V_{DS}$ = 10V, $I_{D}$ = 5A		1		nC
$Q_{gd}$	Gate Drain Charge	1		1.6		nC
t <sub>D(on)</sub>	Turn-On DelayTime			2.4		ns
t <sub>r</sub>	Turn-On Rise Time	$V_{GS}$ =10V, $V_{DS}$ =10V, $R_{L}$ =2.0 $\Omega$ ,		6.4		ns
t <sub>D(off)</sub>	Turn-Off DelayTime	$R_{GEN}$ =3 $\Omega$		38		ns
t <sub>f</sub>	Turn-Off Fall Time	1		9.5		ns
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> =5A, dI/dt=100A/μs		18	24	ns
$Q_{rr}$	Body Diode Reverse Recovery Charge	I <sub>F</sub> =5A, dI/dt=100A/μs		6		nC

A: The value of R  $_{\theta JA}$  is measured with the device mounted on 1in  $^2$  FR-4 board with 2oz. Copper, in a still air environment with T  $_A$  = 25°C. in any given application depends on the user's specific board design. The current rating is based on the t  $\leq$ 10s thermal resistance rating. B: Repetitive rating, pulse width limited by junction temperature.

Rev1 September 2007

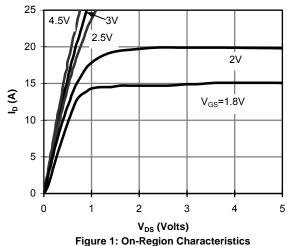
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C. The R  $_{\theta JA}$  is the sum of the thermal impedence from junction to lead R  $_{\theta JL}$  and lead to ambient.

D. The static characteristics in Figures 1 to 6 are obtained using < 300  $\mu s$  pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in  $^2$  FR-4 board with 2oz. Copper, in a still air environment with T  $_A$ =25°C. The SOA curve provides a single pulse rating.

### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



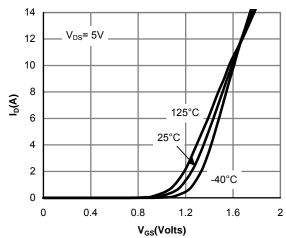


Figure 2: Transfer Characteristics

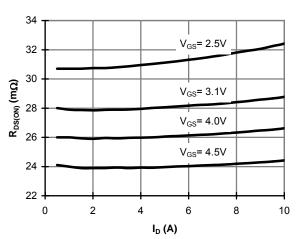


Figure 3: On-Resistance vs. Drain Current and **Gate Voltage** 

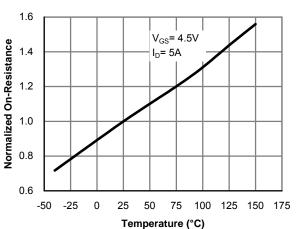


Figure 4: On-Resistance vs. Junction Temperature

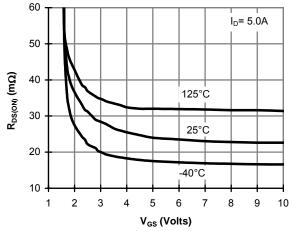


Figure 5: On-Resistance vs. Gate-Source Voltage

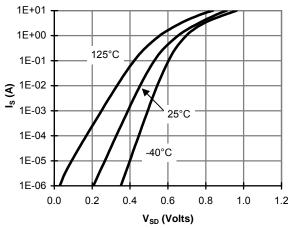


Figure 6: Body-Diode Characteristics

### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

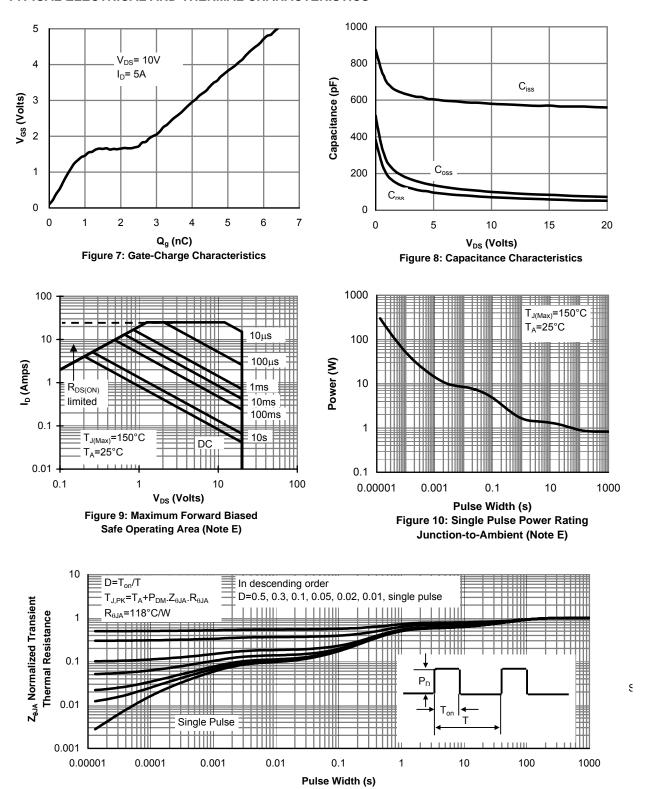


Figure 11: Normalized Maximum Transient Thermal Impedance(Note E)